

# FDMS86300

#### December 2015

# N-Channel PowerTrench<sup>®</sup> MOSFET 80 V, 122 A, 3.9 m $\Omega$

#### **Features**

- Max  $r_{DS(on)}$  = 3.9 m $\Omega$  at  $V_{GS}$  = 10 V,  $I_D$  = 19 A
- Max  $r_{DS(on)}$  = 5.5 m $\Omega$  at  $V_{GS}$  = 8 V,  $I_D$  = 15.5 A
- Advanced Package and Silicon combination for low r<sub>DS(on)</sub> and high efficiency
- Next generation enhanced body diode technology, engineered for soft recovery
- MSL1 robust package design
- 100% UIL tested
- RoHS Compliant

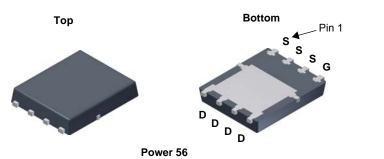


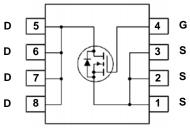
#### **General Description**

This N-Channel MOSFET has been designed specifically to improve the overall efficiency and to minimize switch node ringing of DC/DC converters using either synchronous or conventional switching PWM controllers.It has been optimized for low gate charge, low  $r_{\rm DS(on)}$ , fast switching speed and body diode reverse recovery performance.

# **Applications**

- OringFET / Load Switching
- DC-DC Conversion





MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Parame	eter		Ratings	Units	
$V_{DS}$	Drain to Source Voltage			80	V	
$V_{GS}$	Gate to Source Voltage			±20	V	
	Drain Current -Continuous	T <sub>C</sub> = 25 °C		122		
	-Continuous	T <sub>C</sub> = 100 °C		78	A	
'D	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	19	_ ^	
	-Pulsed		(Note 4)	556		
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	252	mJ	
В	Power Dissipation	T <sub>C</sub> = 25 °C		104	W	
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	2.5	VV	
$T_J, T_{STG}$	Operating and Storage Junction Temperation	ture Range		-55 to +150	°C	

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.2	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	C/VV

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS86300	FDMS86300	Power 56	13 "	12 mm	3000 units

# Electrical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

Symbol	Parameter Test Conditions		Min	Тур	Max	Units
Off Chara	acteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	80			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 μA, referenced to 25 °C		39		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 64 V, V <sub>GS</sub> = 0 V			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±100	nA

#### **On Characteristics**

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2.5	3.4	4.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 μA, referenced to 25 °C		-11		mV/°C
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 19 A		3.2	3.9	
		V <sub>GS</sub> = 8 V, I <sub>D</sub> = 15.5 A		3.8	5.5	mΩ
		$V_{GS}$ = 10 V, $I_D$ = 19 A, $T_J$ = 125 °C		5.0	5.8	
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 19 A		60		S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V - 40 V V - 0 V	5325	7082	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V, f = 1 MHz	957	1272	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 1011 12	26	63	pF
$R_g$	Gate Resistance		1.2		Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time			31	50	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 40 V, I <sub>D</sub> = 19	$V_{DD}$ = 40 V, $I_{D}$ = 19 A, $V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$		43	ns
t <sub>d(off)</sub>	Turn-Off Delay Time				58	ns
t <sub>f</sub>	Fall Time			9	18	ns
$Q_g$	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V		72	86	nC
Qg	Total Gate Charge	V <sub>GS</sub> = 0 V to 8 V	V <sub>DD</sub> = 40 V,	59	71	nC
$Q_{gs}$	Gate to Source Charge		I <sub>D</sub> = 19 A	28.2		nC
Q <sub>ad</sub>	Gate to Drain "Miller" Charge			14.9		nC

#### **Drain-Source Diode Characteristics**

V <sub>SD</sub>	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 2.1 \text{ A}$ (N	lote 2)	0.71	1.2	\/
	Source to Drain Diode Forward voltage	$V_{GS} = 0 \text{ V}, I_S = 19 \text{ A}$ (N	lote 2)	0.81	1.3	v
t <sub>rr</sub>	Reverse Recovery Time	-I <sub>F</sub> = 19 A, di/dt = 100 A/μs		57	90	ns
Q <sub>rr</sub>	Reverse Recovery Charge	- 15 A, αι/αι – 100 A/μs		50	80	nC
t <sub>rr</sub>	Reverse Recovery Time	I <sub>E</sub> = 19 A, di/dt = 300 A/μs		48	77	ns
Q <sub>rr</sub>	Reverse Recovery Charge	-1F - 19 A, αι/αι - 300 A/μS		103	165	nC

#### Notes:

Notes. 1. R<sub>0JA</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0JC</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.



a) 50 °C/W when mounted on a 1 in  $^2$  pad of 2 oz copper



b) 125 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%.
- 3.  $E_{AS}$  of 252 mJ is based on starting  $T_J$  = 25 °C, L = 0.3 mH,  $I_{AS}$  = 41 A,  $V_{DD}$  = 72 V,  $V_{GS}$  = 10 V.
- 4. Pulse Id limited by junction temperature, td  $\leq$  100  $\mu s,$  please refer to SOA curve for more details.

### Typical Characteristics T<sub>.1</sub> = 25 °C unless otherwise noted

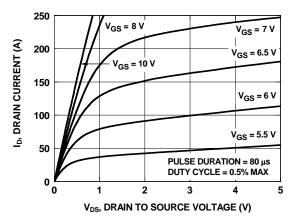


Figure 1. On-Region Characteristics

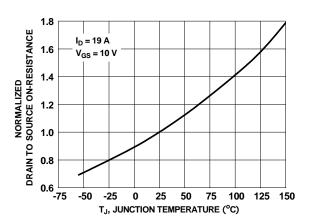


Figure 3. Normalized On-Resistance vs Junction Temperature

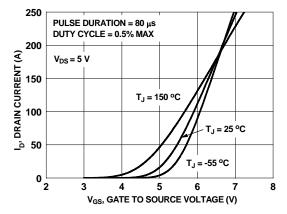


Figure 5. Transfer Characteristics

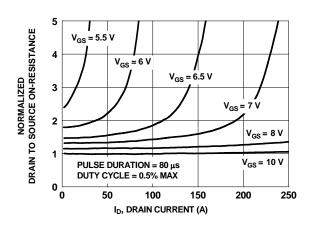


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

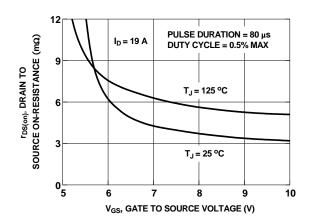


Figure 4. On-Resistance vs Gate to Source Voltage

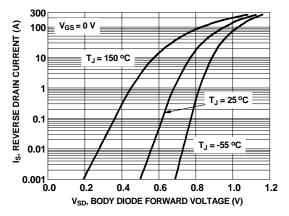


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# Typical Characteristics $T_J$ = 25 $^{\circ}$ C unless otherwise noted

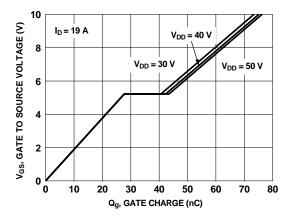


Figure 7. Gate Charge Characteristics

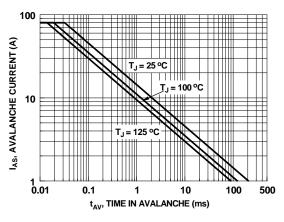


Figure 9. Unclamped Inductive Switching Capability

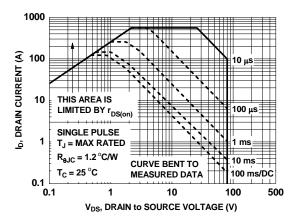


Figure 11. Forward Bias Safe Operating Area

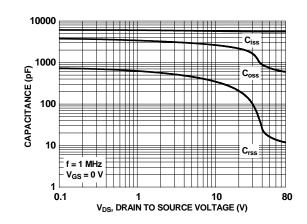


Figure 8. Capacitance vs Drain to Source Voltage

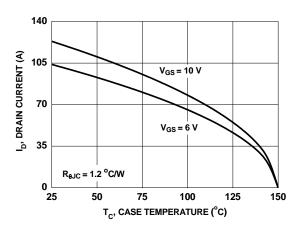


Figure 10. Maximum Continuous Drain Current vs Case Temperature

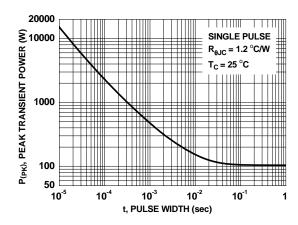


Figure 12. Single Pulse Maximum Power Dissipation

# **Typical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

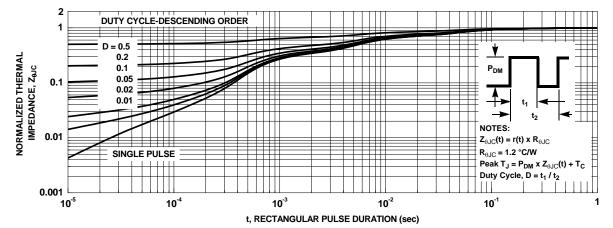
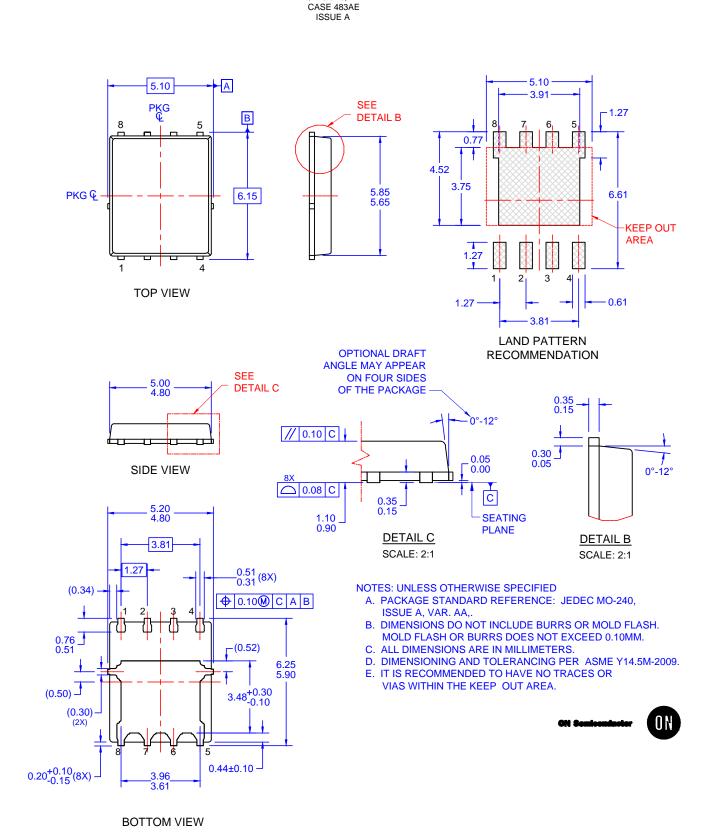


Figure 13. Junction-to-Case Transient Thermal Response Curve



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